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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

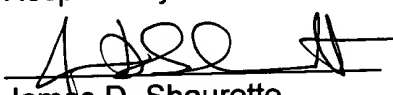
Application Serial No. .... 09/512,968  
Filing Date ..... February 24, 2000  
Inventor ..... David R. Hembree  
Assignee ..... Micron Technology, Inc.  
Group Art Unit ..... 2858  
Examiner ..... V. Nguyen  
Attorney's Docket No. .... MI22-1363  
Title: Electronic Device Workpiece Processing Apparatus and Method of Communicating  
Signals Within an Electronic Device Workpiece Processing Apparatus

INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

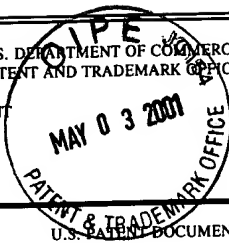
The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No admission is made regarding whether all the submitted references are prior art.

Dated: 4/30/01

Respectfully submitted,  
  
James D. Shaurette  
Reg. No. 39,833

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Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
M122-1363SERIAL NO.  
09/512,968LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
Micron Technology, Inc.FILING DATE  
February 24, 2000PRIORITY GROUP  
2858

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AE	<del>S/N: 09/032,184; Filed 2/27/98; Akram et al.; Amendment filed 12/18/00; CPA filed 7/23/00; Amendment filed 2/3/00; Amendment filed 8/23/99;</del> Original Application filed 2/27/98; Pending Claims.
	AF	Advertisement for Probe Technology; <a href="http://www.idinet.com">www.idinet.com</a> ; Interconnect Devices, Inc.; 1 page; 3/6/98
	AG	Good Things Come In Small BGA/CSP Packages; <a href="http://www.johnstech.com/4/handbook/page9.html">www.johnstech.com/4/handbook/page9.html</a> ; 1 page; 3/5/98
	AH	Product Description for Double Ended Probes, B1052 Series; <a href="http://www.testprobe.com/products/b1052.html">www.testprobe.com/products/b1052.html</a> ; Rika Denshi America, Inc.; 1 page; 2/4/98.
	AI	Product Description for Test Centers, RM-500 Series Probes, <a href="http://www.testprobe.com/products/rm500.html">www.testprobe.com/products/rm500.html</a> ; Rika Denshi America, Inc.; 1 page; 2/4/98.
	AJ	Product Description for Cost Effective Interconnections for High I/O Products; <a href="http://www.testprobe.com/products/io.htm#b1303">www.testprobe.com/products/io.htm#b1303</a> ; Rika Denshi America, Inc.; 1 page; 2/4/98.
	AK	Product Description for Ball Grid Probe B1303-C3; <a href="http://www.testprobe.com/products/io.htm#b1303">www.testprobe.com/products/io.htm#b1303</a> ; Rika Denshi America, Inc.; 1 page; 2/4/98.
	AL	Product Description for Test Socket Contacts; <a href="http://www.johnstech.com/4/handbook/page9.html">www.johnstech.com/4/handbook/page9.html</a> ; 1 page; 3/5/98

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.